

Supporting information

Scanning Near-Field Ellipsometry Microscopy: Imaging Nanomaterials with Resolution Below the Diffraction Limit

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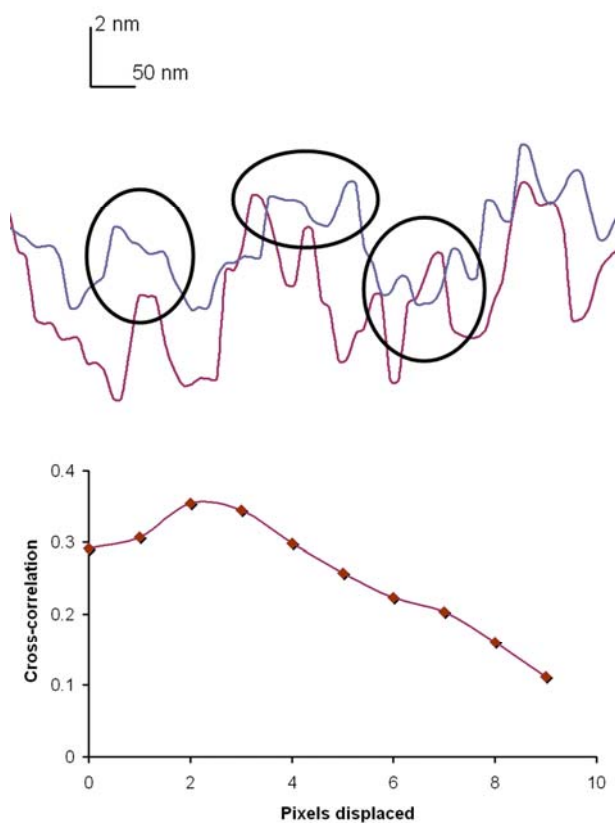


Figure S-1. Top: Section of a scan line of Figure 7, showing the superposition of the topographic (purple) and optical (blue) signals. A mismatch between the two profiles is observed, as pointed out by circles in the figure. Bottom: cross correlation between two (topography and optical) profiles obtained from Figure 7. It is shown that correlation shows a maximum if the optical profile is shifted of 2 pixels to the right.